

Scanning electron microscope

Description/Parameters

Scanning electron microscope Tescan Vega (Tungsten emitter) with secondary electrons (SE), backscattered electrons (BSE) and energy-dispersive X-ray spectroscopy (EDS) detectors. Ability to analyse different kind of samples such as: non-organic, organic and biological (dry samples), metallurgical, geological in powder or bulk form. Maximum sample size: 40mm by 40 mm (width and height). Possibility of sample tilt (up to approx. 72°) and rotation (360°). For non-conductive samples, the additional gold sputtering is performed (Quorum Q150R ES plus sputter).

Utilization/Services

- Analysis of sample microstructure
- Analysis of sample chemical composition (point, line and elements distribution mapping)

